

**Notice of References Cited**

Application/Control No.

10/524,444

Applicant(s)/Patent Under

Reexamination

MOCHIZUKI ET AL.

Examiner

HENOK G. HEYI

Art Unit

2627

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,002,834 A	12-1999	Hirabayashi et al.	386/70
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	J	US-			
	K	US-			
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	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

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